

## 17.9 References

### Relevant paper for section 17.2

H.O.Porter, D.W.Turner: A descriptive classification of the electron Spectroscopies  
PAC 59 (10) 1343-1406 (1987)

### Relevant paper for section 17.3

M.Grasserbauer, K.F.J.Heinrich, G.H.Morrison: Nomenclature, symbols, and units recommended for in situ microanalysis  
PAC 55 (12) 2023-2027 (1983)

### Relevant paper for section 17.4

G.H.Morrison, K.L.Cheng, M.Grasserbauer: General aspects of trace analytical method - IV: Recommendations for nomenclature, standard procedures and reporting of experimental data for surface analysis techniques  
PAC 51 2243-2250 (1979)

### Relevant paper for section 17.6

N.Sheppard: English-derived abbreviations for experimental techniques in surface science and chemical spectroscopy  
PAC 63 (6) 887-893 (1991)

### Relevant paper for section 17.7

J.H.Block, A.M.Bradshaw, P.C.Gravelle, J.Haber, R.S.Hansen, M.W.Roberts, N.Sheppard, K.Tamaru: A survey of experimental techniques in surface chemical physics.  
PAC 62 (12) 2297-2322 (1990)

Related paper for section 17.2

Nomenclature and spectral presentation in electron spectroscopy resulting from excitation by photons (recommendations 1975)

PAC 45 (1) 221-224 (1976)

Related papers for section 17.8

M.Grasserbauer: Critical evaluation of calibration procedures for distribution analysis of dopant elements in silicon and gallium arsenides

PAC 60 (3) 437-444 (1988)

A.Galuska, G.H.Morrison: Distribution analysis of major and trace elements through semiconductor layers of changing matrix using secondary ion mass spectrometry (SIMS)

PAC 59 (2) 229-244 (1987)